

The advanced MXE pyrometer combines speed and precision, enabling accurate, non-contact, repeatable measurement and control of demanding applications. Its high-speed (up to 10 kHz) performance is ideal for processes with moving targets, such as rotating substrates. It is also extremely well suited for dynamic processes, including laser-based processing or spot anneals. For easy integration and flexible control systems, the MXE unit is remarkably compact and supports a variety of I/O protocols.

## Features

- In-situ, non-contact temperature and emissivity measurement
- High-speed measurement ideal for a variety of applications
- Variety of available temperature + reflectance wavelengths
- EtherCAT, USB, and analog output options

## Benefits

- Increased process insight
- Highly configurable platform
- Improved temperature measurement accuracy and repeatability
- Enhanced uniformity
- Increased productivity, yield, and throughput
- Decreased development time
- Comprehensive measurement capabilities
- Easy integration and flexible control



*MXE pyrometer*

### INCREASED-PROCESS INSIGHT

Temperature control is increasingly critical in a variety of applications. The MXE pyrometer is ideally suited to measure temperature in tightly controlled applications where uniform, repeatable measurements are required.

### HIGHLY CONFIGURABLE PLATFORM

The MXE pyrometer is configurable to suit a variety of applications. Features such as measurement wavelength, active reflectance, optical interface, and I/O protocols can be optimized for a specific application. Measurements up to 10 kHz are possible.

In addition, a variety of spot sizes and working distances can be supported. Use of fiber-coupled collection optics can also be supported for applications requiring remote placement of the electronics.

### ACCURATE, REPEATABLE PERFORMANCE

High-speed measurement allows collection of multiple data points and ensures statistically significant temperature determination. Moreover, built-in compensation algorithms allow stable operation over the full ambient temperature range for repeatable and consistent measurement.

### COMPREHENSIVE MEASUREMENT CAPABILITIES

Measurement wavelength can be selected specifically for the target and temperature range of interest, ensuring optimal results. Reflectance is also available, allowing for emissivity-compensated measurements on opaque targets.